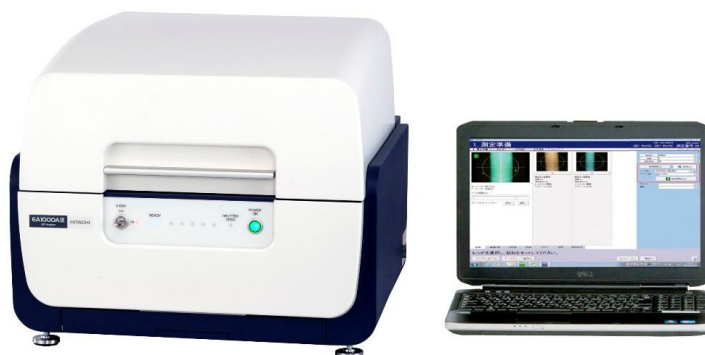


November 12, 2013

Launch of the EA1000AIII, X-Ray Fluorescence Analyzer for Screening of Hazardous Substances

Hitachi High-Tech Science Corporation announced worldwide release of the EA1000AIII for controlling hazardous substances regulated by European Union directives such as WEEE and RoHS. The EA1000AIII is the latest generation instrument with higher performance and convenience, and affordable price. Together with the EA1000VX released last September 2013, the EA1000AIII will meet the users' demand for controlling hazardous substances.



X-Ray Fluorescence Analyzer EA1000AIII

Average measurement time of the EA1000AIII is reduced to one-third of its former model SEA1000AII by newly equipped Si semiconductor detector and a faster electronics and mechanical system; however, the price remains the same as SEA1000AII. In addition, our controlled substances measurement software version 2 is added as a standard feature which was optional software previously. Furthermore, features such as sample material identification function, easy door opening mechanism, progress bar on front panel which indicates the measurement progress, and liquid nitrogen free realizes efficient inspection.

Environmental regulations were applied to a variety of products such as automobiles, home electronics, and toys. The number of elements to be controlled has been increasing recently such as halogen. These regulations are important factor among full supply chain from raw material suppliers to assembly manufacturers.

Key Features

-Fast measurement

Measurement time is one third compared to our conventional model SEA1000AII (mean time when measuring plastics and brasses). Progress bar on operation panel shows you the progress status of measurement at a glance.



-Data management

Our controlled substances measurement software version 2 enables users to see a trend of acquired data and provides a report of the results.

-Applicable to many elements

The EA1000AIII controls many hazardous substances other than RoHS restricted elements (Cd, Pb, Hg, Br, and Cr) such as chlorine (Cl).

-Liquid nitrogen free

Liquid nitrogen is not required same as conventional one.

Key Specifications

Measurement Principle	Energy-dispersive x-ray fluorescence
Measurement Elements	Atomic Number Al (Z=13) – U(Z=92)
Detector	Si semiconductor detector (Liquid nitrogen free)
Performance (Measurement Time of Cd,Pb,Hg,Br,Cr) ^{Note}	Approximately 70sec
Chamber Size	W370 x D320 x H120 mm
Sample Chamber (Optional)	Maximum 12 samples
Dimensions	W520 x D600 x H445 mm
Weight	Approximately 59kg

Note: This is an example of a test result under Hitachi High-Tech Science’s measurement condition.

About Hitachi High-Tech Science Corporation

Hitachi High-Tech Science is a subsidiary wholly owned by Hitachi High-Technologies Corporation (TOKYO: 8036). The company develops, manufactures and sells measurement and analysis instruments. For additional information, visit: <http://www.hitachi-hitec-science.com/en/index.shtml>

Product website

<http://www.hitachi-hitec-science.com/en/products/xrf/EA1000AIII.html>

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